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MOTOROLA SEMICONDUCTOR • **TECHNICAL DATA**

Designer's Data Sheet

Power Field Effect Transistor N-Channel Enhancement-Mode Silicon Gate

This Logic Level TMOS Power FET is designed for high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

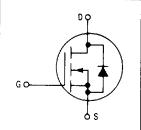
- Low Drive Requirement to Interface Power Loads to Logic Level ICs or Microprocessors — V_{GS(th)} = 2 Volts max
- Silicon Gate for Fast Switching Speeds Switching Times Specified at 100°C
- Designer's Data IDSS, VDS(on), VGS(th) and SOA Specified at Elevated Temperature
- Rugged SOA is Power Dissipation Limited
- Source-to-Drain Diode Characterized for Use With Inductive Loads

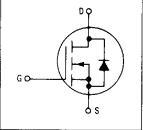


MTP15N05EL

Motorola Preferred Device

TMOS POWER FET LOGIC LEVEL 15 AMPERES $R_{DS(on)} = 0.1 \text{ OHM}$ 50 VOLTS







MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	50	Vdc
Drain-Gate Voltage (R _{GS} = 1 MΩ)	V _{DGR}	50	Vdc
Gate-Source Voltage Continuous Non-repetitive ($t_p \le 50 \mu s$)	V _{GS} V _{GSM}	± 15 ± 20	Vdc Vpk
Drain Current — Continuous — Pulsed	IDM IDM	15 40	Adc
Total Power Dissipation @ T _C = 25°C Derate above 25°C	PD	75 0.6	Watts W/°C
Operating and Storage Temperature Range	T _J , T _{stg}	-65 to 150	°C

THERMAL CHARACTERISTICS

Thermal Resistance Junction to Case	R _{ØJC}	1.67	°C/W	
Junction to Ambient MTM15N05L/06L MTP15N05L/06L	$R_{\theta JA}$	30 62.5		
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	TL	260	°C	

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Drain-Source Breakdown Voltage (VGS = 0, ID = 1 mA) MTM/MTP15N05L MTM/MTP15N06L	V _{(BR)DSS}	50 60	_	Vdc
Zero Gate Voltage Drain Current {VDS = Rated VDSS, VGS = 0} {VDS = Rated VDSS, VGS = 0, TJ = 125°C}	IDSS	<u></u>	1 50	μAdc

(continued)

Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented SOA Limit curves — representing boundaries on device characteristics — are given to facilitate "worst case" design

Preferred device is a Motorola recommended choice for future use and best overall value.

ELECTRICAL CHARACTERISTICS — continued ($T_C = 25^{\circ}C$ unless otherwise noted)

Cha	racteristic	Symbol	Min	Max	Unit
FF CHARACTERISTICS (continue	d)				
Gate-Body Leakage Current, For	ward ($V_{GSF} = 15 \text{ Vdc}, V_{DS} = 0$)	IGSSF	_	100	nAdc
Gate Body Leakage Current, Rev	verse (V _{GSR} = 15 Vdc, V _{DS} = 0)	IGSSR	_	100	nAdc
N CHARACTERISTICS					
Gate Threshold Voltage (VDS = VGS, ID = 1 mA) (TJ = 100°C)		VGS(th)	1 0.75	2 1.5	Vdc
Static Drain-Source On-Resistan (VGS = 5 Vdc, ID = 7.5 Adc)	се	R _{DS(on)}	_	0.1	Ohm
Drain-Source On-Voltage (VGS (ID = 15 Adc) (ID = 7.5 Adc, TJ = 100°C)	= 5 V)	V _{DS(on)}	_	3 1.5	Vdc
Forward Transconductance (VD)	S = 15 V, I _D = 7.5 A)	9FS	5	-	mhos
YNAMIC CHARACTERISTICS					
	V _{DS} = 25 V, V _{GS} = 0, f = 1 MHz			900	pF
Input Capacitance	V _{GS} = 15 V, V _{DS} = 0, f = 1 MHz See Figure 4	C _{iss}		2800	
	V _{DS} = 25 V, V _{GS} = 0, f = 1 MHz		_	200	
Reverse Transfer Capacitance	V _{GS} = 15 V, V _{DS} = 0, f = 1 MHz See Figure 4	C _{rss}	-	2400	pF
Output Capacitance	V _{DS} = 25 V, V _{GS} = 0, f = 1 MHz See Figure 4	Coss	_	450	pF
WITCHING CHARACTERISTICS (T _J = 100°C)				
Turn-On Delay Time		td(on)	_	40	ns
Rise Time	$(V_{DD} = 25 \text{ V, I}_{D} = 7.5 \text{ A,}$	t _r	_	260	
Turn-Off Delay Time	V _{GS} = 5 V, R _{gen} = 50 ohms)	td(off)	_	200	
Fall Time		tf	_	200	
Total Gate Charge	· (V _{DS} = 0.8 Rated V _{DSS} ,	α_{g}	14 (typ)	22	nC
Gate-Source Charge	I _D = 15 A, V _{GS} = 5 Vdc)	Qgs	7 (typ)	_]
Gate-Drain Charge	See Figures 6 and 10.	Ogd	7 (typ)	_	
OURCE DRAIN DIODE CHARACT	ERISTICS				
Forward On-Voltage		V _{SD}	1.8 (typ)		Vdc
Forward Turn-On Time	(I _S = Rated I _D , V _{GS} = 0)	ton	Limited by stray inductance		
Reverse Recovery Time		t _{rr}	300 (typ)		ns
TERNAL PACKAGE INDUCTANO	CE (TO-220)				
Internal Drain Inductance (Measured from the contact s (Measured from the drain lea	crew on tab to center of die) d 0.25" from package to center of die)	Ld	3.5 (Typ) 4.5 (Typ)	_	nH
Internal Source Inductance (Measured from the source le source bond pad.)	ad 0.25" from package to	L _S	7.5 (Typ)	_	

BAE D TYPICAL CHARACTERISTICS

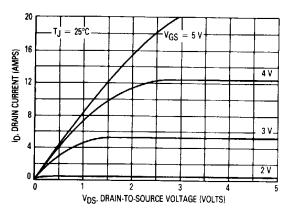


Figure 1. On-Region Characteristics

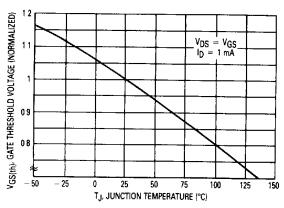


Figure 2. Gate-Threshold Voltage Variation With Temperature

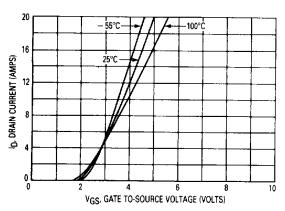


Figure 3. Transfer Characteristics

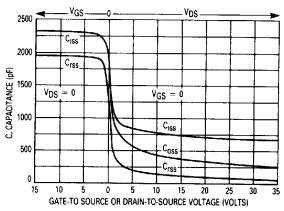


Figure 4. Capacitance Variation

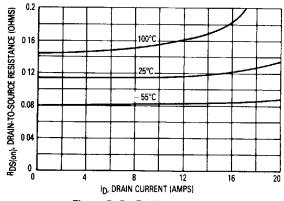


Figure 5. On-Resistance versus **Drain Current**

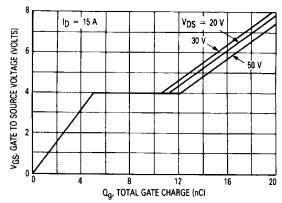
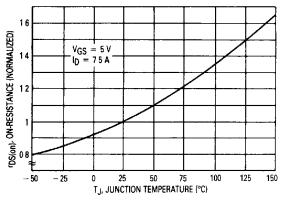


Figure 6. Gate Charge Variation



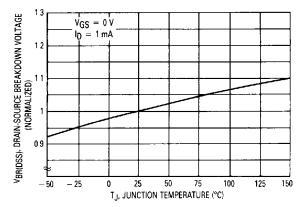


Figure 7. On-Resistance Variation with Temperature

Figure 8. Drain-Source Breakdown Voltage Variation with Temperature

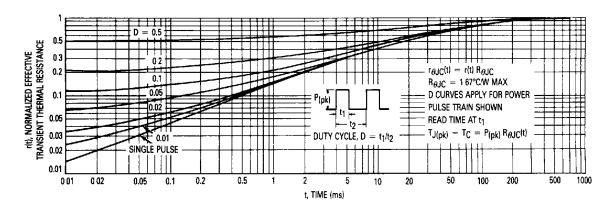


Figure 9. Thermal Response

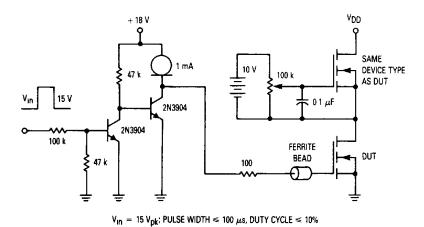


Figure 10. Gate Charge Test Circuit

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SAFE OPERATING AREA INFORMATION

FORWARD BIASED SAFE OPERATING AREA

The FBSOA curves define the maximum drain-tosource voltage and drain current that a device can safely handle when it is forward biased, or when it is on, or being turned on. Because these curves include the limitations of simultaneous high voltage and high current, up to the rating of the device, they are especially useful to designers of linear systems. The curves are based on a case temperature of 25°C and a maximum junction temperature of 150°C. Limitations for repetitive pulses at various case temperatures can be determined by using the thermal response curves. Motorola Application Note, AN569, "Transient Thermal Resistance-General Data and Its Use" provides detailed instructions.

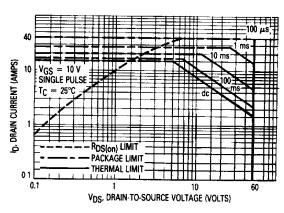


Figure 11. Maximum Rated Forward **Biased Safe Operating Area**

SWITCHING SAFE OPERATING AREA

The switching safe operating area (SOA) of Figure 12 is the boundary that the load line may traverse without incurring damage to the MOSFET. The fundamental limits are the peak current, IDM and the breakdown voltage, V(BR)DSS. The switching SOA shown in Figure 12 is applicable for both turn-on and turn-off of the devices for switching times less than one microsecond.

The power averaged over a complete switching cycle must be less than:

$$\frac{\mathsf{T}_{\mathsf{J}(\mathsf{max})} - \mathsf{T}_{\mathsf{C}}}{\mathsf{R}_{\theta \mathsf{J}\mathsf{C}}}$$

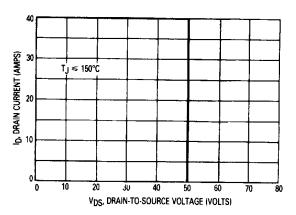


Figure 12. Maximum Rated Switching Safe Operating Area